Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination TAKINAMI ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,833,769 B2	12-2004	Seppinen et al.	331/177V
	В	US-6,509,805 B2	01-2003	Ochiai, Toshiyuki	331/117FE
	С	US-6,774,736 B1	08-2004	Kwek et al.	331/177V
	D	US-2001/0050598	12-2001	Mourant et al.	331/117.00R
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	_	US-			
	J	US-			
	К	US-	ĺ		
	L	US-			<u>, , , , , , , , , , , , , , , , , , , </u>
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	σ	1.5				
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.